

Search Notes



Application/Control No.

10/670,915

Examiner

Devesh Khare

Applicant(s)/Patent under Reexamination

DAIFUKU ET AL.

Art Unit

1623

SEARCHED

Class	Subclass	Date	Examiner
514	395, 12, 232.8, 307, 336 352, 388, 50, 48		
536	23.7, 28.4, 28.1, 28.3		
544	10 6, 131 140		
549	282		
548	331.5	11/13/06	du
Search updated		4/30/07	du

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
STIC ST ^r Search	6/8/06	du
Inventor Search (Palm, STIC)	11/9/06	du
PLVS Search	5/17/06	du
East Search updated	4/30/07	du